

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/004,019	TOH ET AL.
	Examiner	Art Unit
	Shin-Hon Chen	2131

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
713	168,178	11/29/2005	S.C.
709	205	2/23/2005	S.C.
380	30	2/23/2005	S.C.